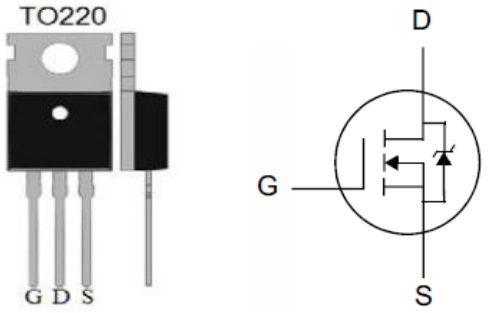
40V N-Channel MOSFET

Lead Free Package and Finish

BV_{DSS}	$R_{DS(ON),typ.}$	I_D[2]
40V	1.3mΩ	345A

General Features

- Proprietary New Trench Technology
- Ultra-low Miller Charge
- $R_{DS(ON),typ.}$=1.3 m Ω@V_{GS}=10V
- Low Gate Charge Minimize Switching Loss
- Fast Recovery Body Diode



Applications

- High efficiency DC/DC Converters
- Synchronous Rectification
- Motor Drive

Ordering Information

Part Number	Package	Brand
PTP01N04N	TO-220	

Absolute Maximum Ratings

T_C=25℃ unless otherwise specified

Symbol	Parameter	PTP01N04N	Unit
V_{DSS}	Drain-to-Source Voltage[1]	40	V
V_{GSS}	Gate-to-Source Voltage	±20	
I_D	Continuous Drain Current[2] V_{GS} @ 10V	345	A
	Continuous Drain Current[3] V_{GS} @ 10V	196	
	Continuous Drain Current[2] T_C = 100°C, V_{GS} @ 10V	244	
I_{DM}	Pulsed Drain Current at V_{GS}=10V[2,4]	1380	
E_{AS}	Single Pulse Avalanche Energy(L=1Mh,	2000	mJ
dv/dt	Peak Diode Recovery dv/dt[3]	5.0	V/ns
P_D	Power Dissipation	375	W
	Derating Factor above 25℃	2.5	W/℃
T_L T_{PAK}	Maximum Temperature for Soldering Leads at 0.063in (1.6mm) from Case for 10 seconds, Package Body for 10 seconds	300 260	℃
T_J& T_{STG}	Operating and Storage Temperature Range	-55 to 175	

Caution: Stresses greater than those listed in the "Absolute Maximum Ratings" may cause permanent damage to the device.

Thermal Characteristics Maximum Ratings

Symbol	Parameter	PTP01N04N	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	0.4	℃/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62	

Electrical Characteristics

OFF Characteristics

T_J =25℃ unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	40	--	--	V	V_{GS}=0V, I_D=250uA
I_{DSS}	Drain-to-Source Leakage Current	--	--	1	uA	V_{DS}=40V, V_{GS}=0V
		--	--	100		V_{DS}=32V, V_{GS}=0V, T_J =125℃
I_{GSS}	Gate-to-Source Leakage Current	--	--	+100	nA	V_{GS}=+20V, V_{DS}=0V
		--	--	-100		V_{GS}=-20V, V_{DS}=0V

ON Characteristics

T_J =25℃ unless otherwise specified

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions
$R_{DS(ON)}$	Static Drain-to-Source On-Resistance	--	1.3	1.5	mΩ	V_{GS}=10V, I_D=196A [3]
$V_{GS(TH)}$	Gate Threshold Voltage	2.0	--	4.0	V	V_{DS}=V_{GS}, I_D=250uA

Dynamic Characteristics

Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions	
C_{iss}	Input Capacitance	--	10.8	--	nF	V_{GS}=0V, V_{DS}=25V, f=1.0MH_Z	
C_{rss}	Reverse Transfer Capacitance	--	0.9	--			
C_{oss}	Output Capacitance	--	1.6	--			
R_G	Gate Series Resistance	--	2.0	--	Ω	f=1.0MH_Z	
Q_g	Total Gate Charge	--	148	--	nC	V_{GS}=0 to 10V	V_{DD}=20V, I_D=185A,
		--	88	--		V_{GS}=4.5V	
Q_{gs}	Gate-to-Source Charge	--	35	--			
Q_{gd}	Gate-to-Drain (Miller) Charge	--	42	--			

Resistive Switching Characteristics

Essentially independent of operating temperature

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions
$t_{d(ON)}$	Turn-on Delay Time	--	29	--	nS	V_{DD}=26V, I_D=195A, V_{GS}= 10V R_G=2.1Ω
t_{rise}	Rise Time	--	30	--		
$t_{d(OFF)}$	Turn-Off Delay Time	--	145	--		
t_{fall}	Fall Time	--	43	--		

Source-Drain Body Diode Characteristics

T_J=25℃ unless otherwise specified

Symbol	Parameter	Min	Typ.	Max.	Unit	Test Conditions
I_{SD}	Continuous Source Current[2]	--	--	345	A	Integral PN-diode in MOSFET
I_{SM}	Pulsed Source Current[2]	--	--	1380		
V_{SD}	Diode Forward Voltage	--	--	1.3	V	I_S=195A, V_{GS}=0V
trr	Reverse recovery time	--	81	--	nS	V_R=34V,V_{GS}=0V ,I_F=195A, di_F/dt=100A/μs
	Reverse recovery time, T_J = 125°C	--	85	--		
Qrr	Reverse recovery charge	--	70	--	nC	
	Reverse recovery charge, T_J = 125°C	--	83	--		
IRRM	Reverse Recovery Current	--	1.7	--	A	

Note:

[1] T_J=+25℃ to +175℃ .
[2] Silicon limited current only.
[3] Package limited current.
[4] Repetitive rating; pulse width limited by maximum junction temperature.
[5] Pulse width≤380μs; duty cycle≤2%.

Typical Characteristics

Figure 1. Maximum Transient Thermal Impedance

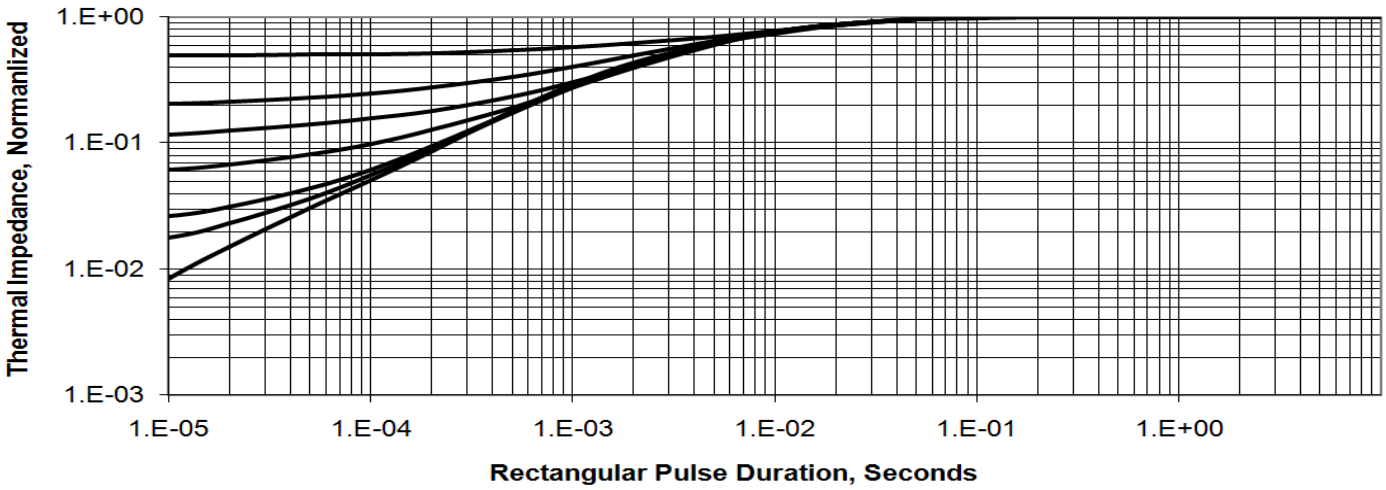


Figure 2 . Maximum Power Dissipation vs Case Temperature

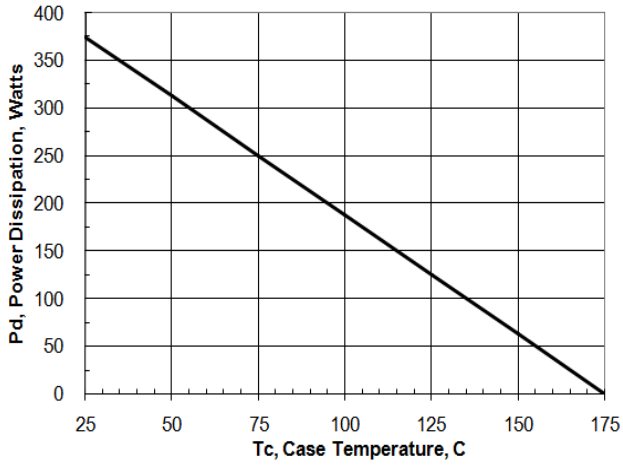


Figure 3 .Maximum Continuous Drain Current vs Case Temperature

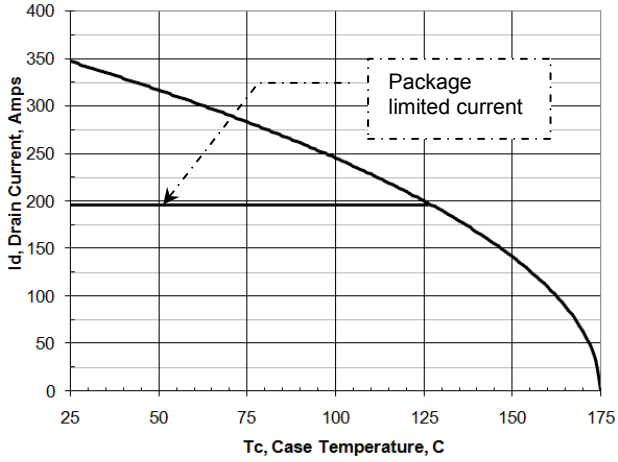


Figure 4. Typical Output Characteristics

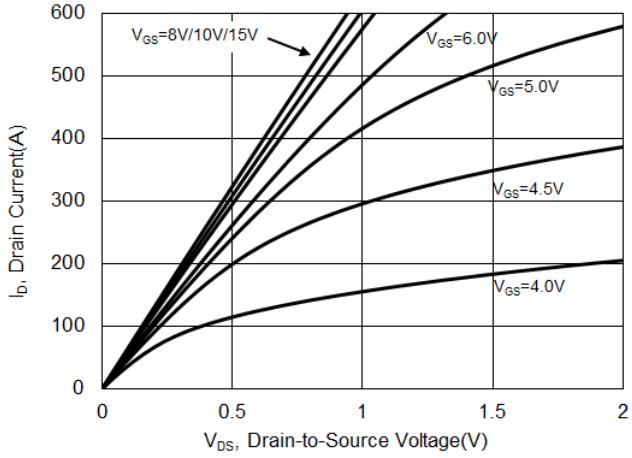
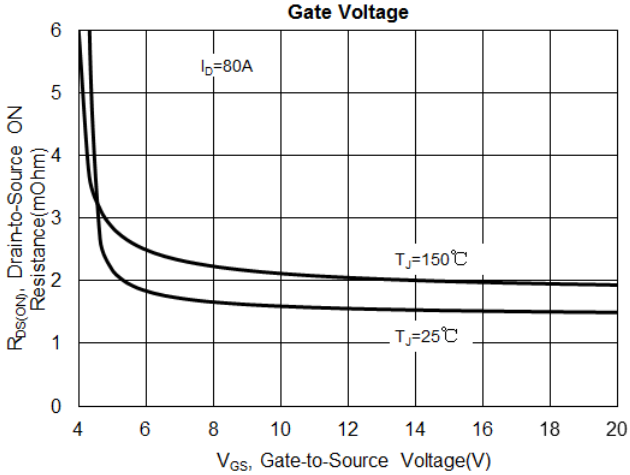


Figure 5. Typical Drain-to-Source ON Resistance vs. Gate Voltage



Typical Characteristics(Cont.)

Figure 6. Peak Current Capability

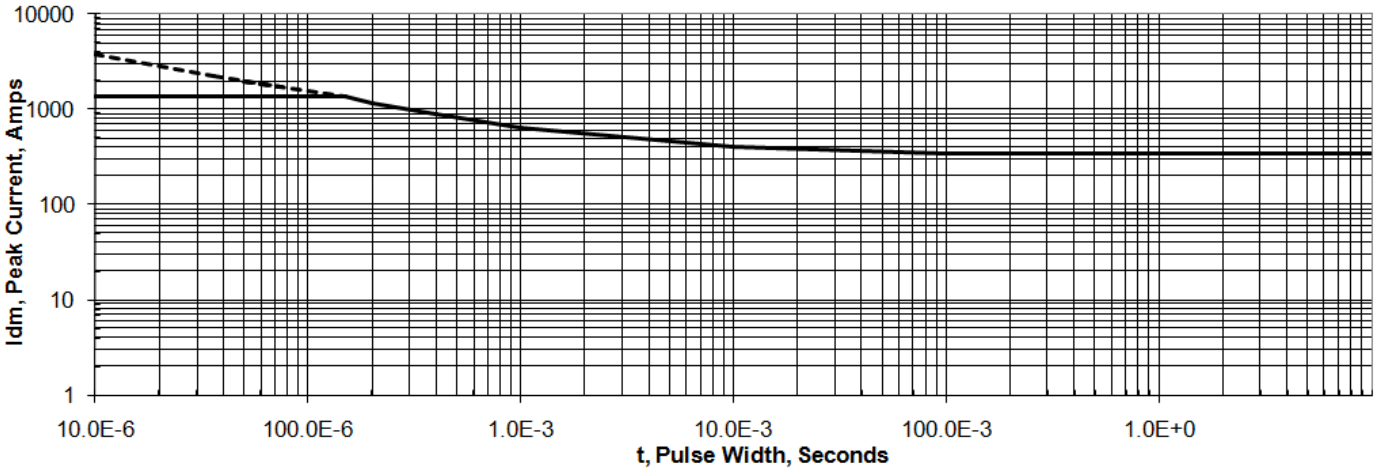


Figure 7. Typical Transfer Characteristics

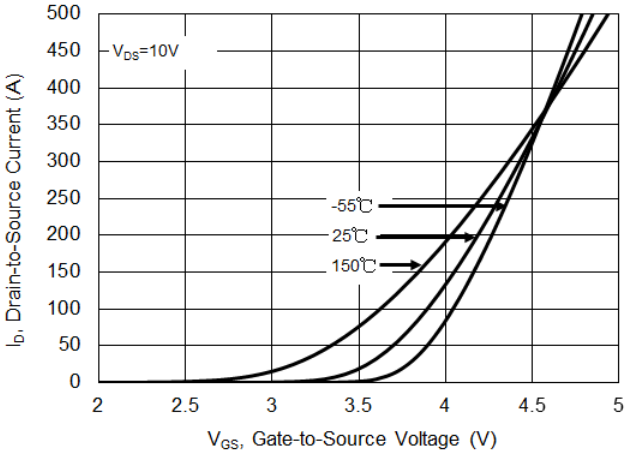


Figure 8. Unclamped Inductive Switching Capability

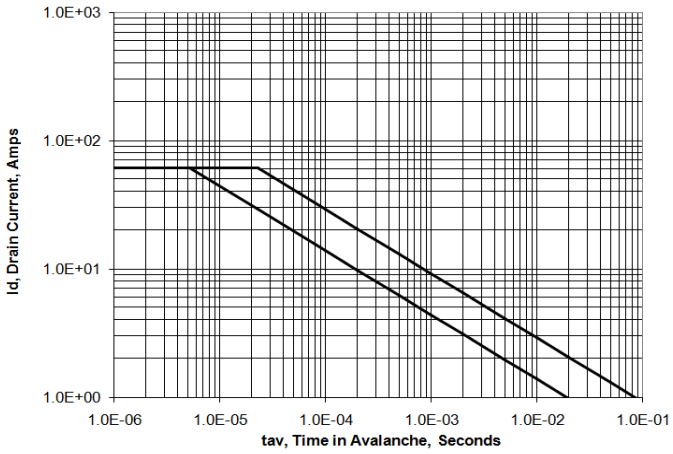


Figure 9. Typical Drain-to-Source ON Resistance

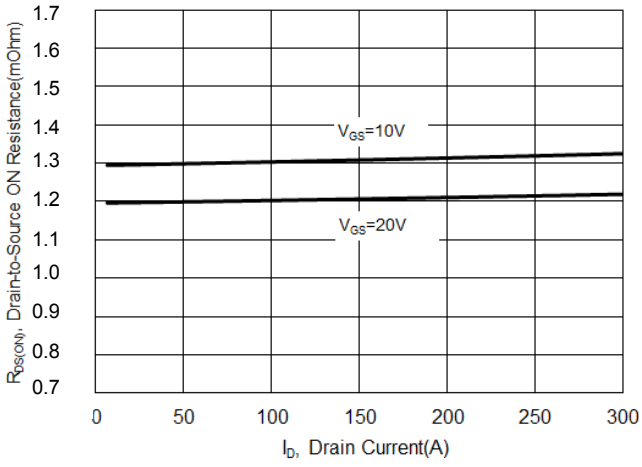
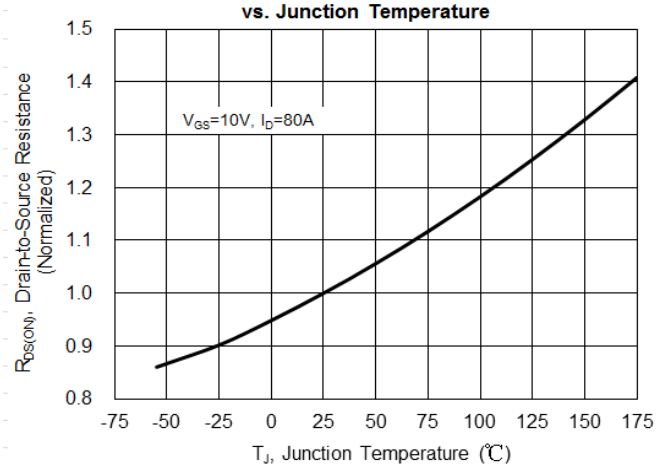


Figure 10. Typical Drain-to-Source On Resistance vs. Junction Temperature



Typical Characteristics(Cont.)

Figure 11.Typical Breakdown Voltage vs. Junction Temperature

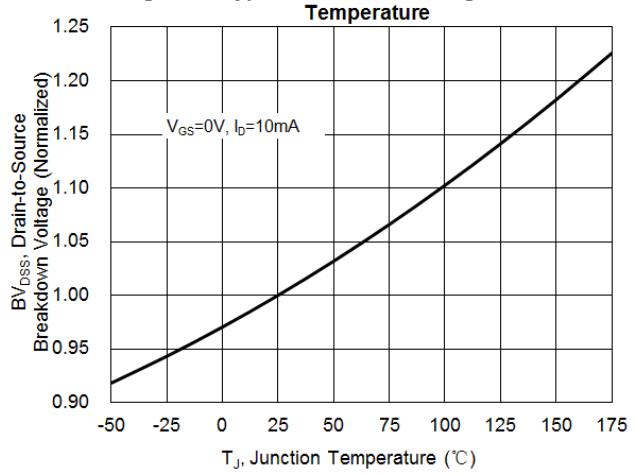


Figure 12.Typical Threshold Voltage vs. Junction Temperature

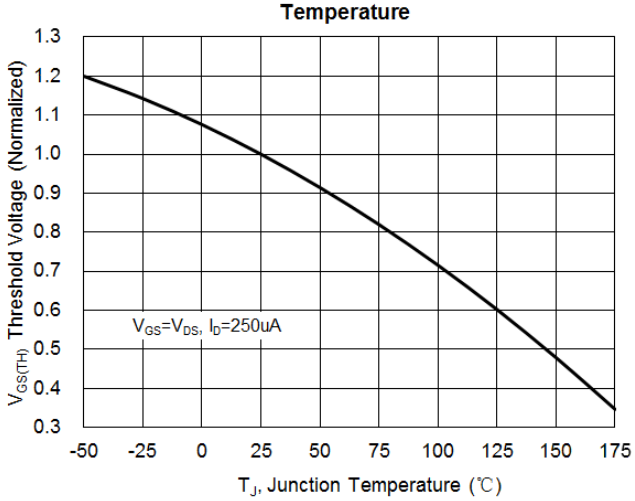


Figure 13 . Maximum Safe Operating Area

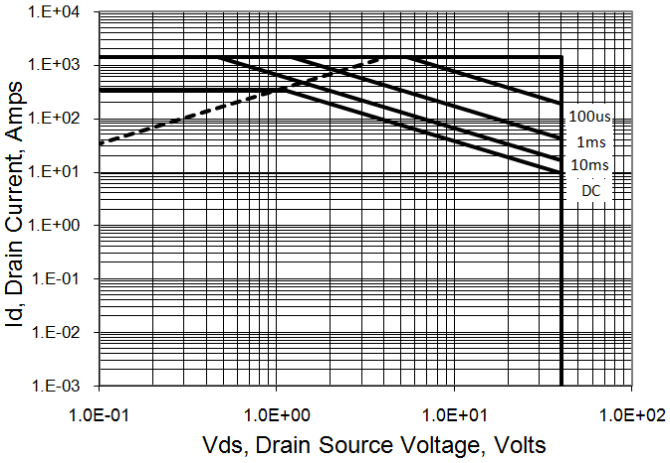


Figure 14. Capacitance vs Vds

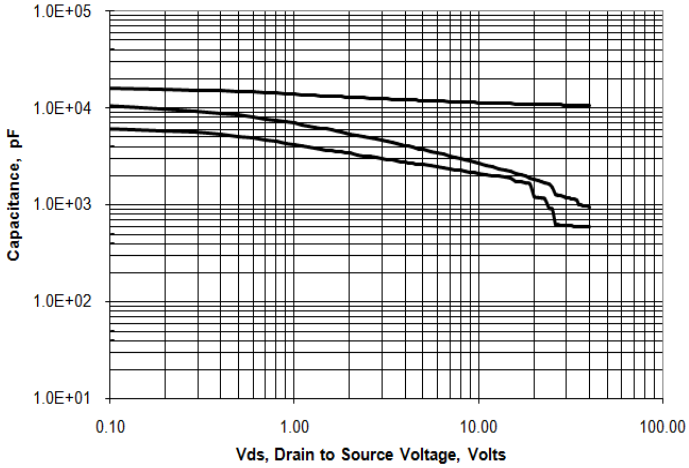


Figure 15 .Typical Gate Charge

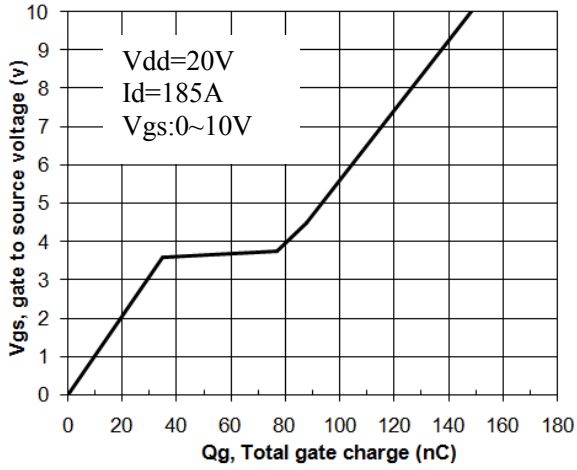
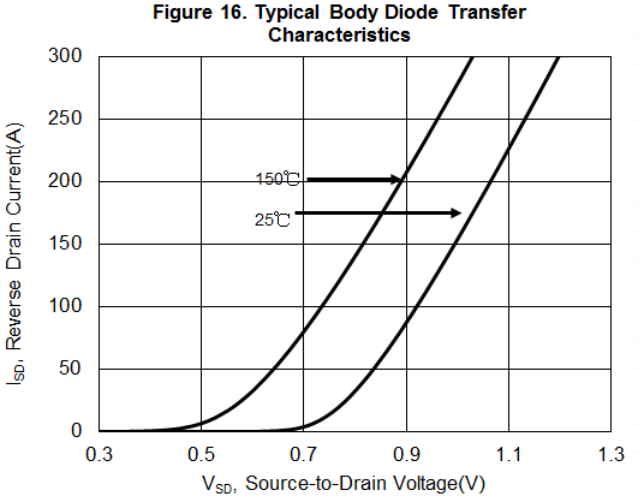


Figure 16. Typical Body Diode Transfer Characteristics



Test Circuits and Waveforms

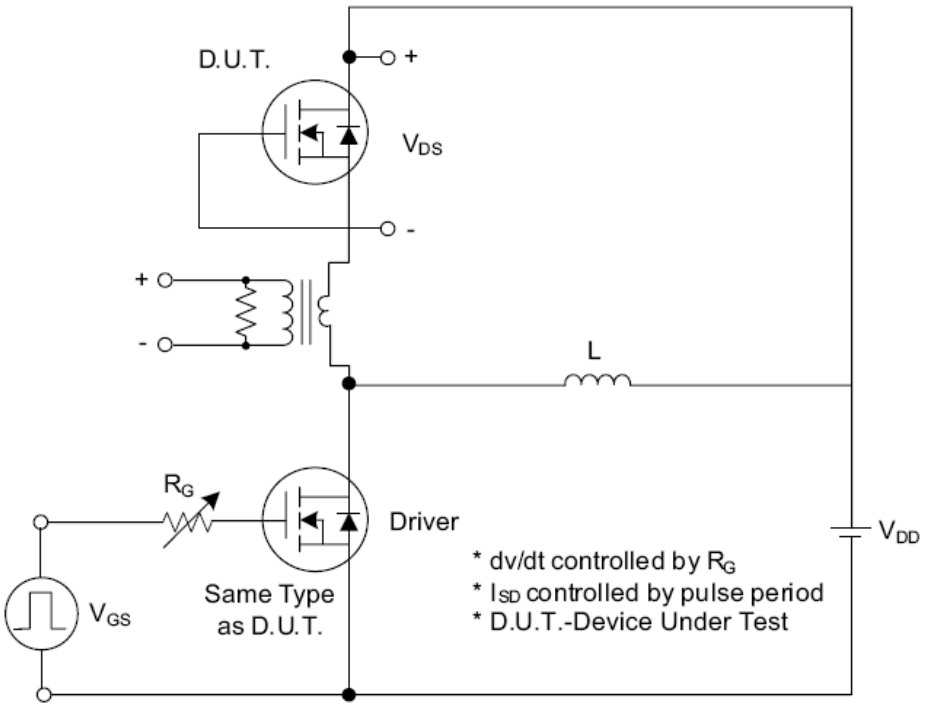


Fig. 1.1 Peak Diode Recovery dv/dt Test Circuit

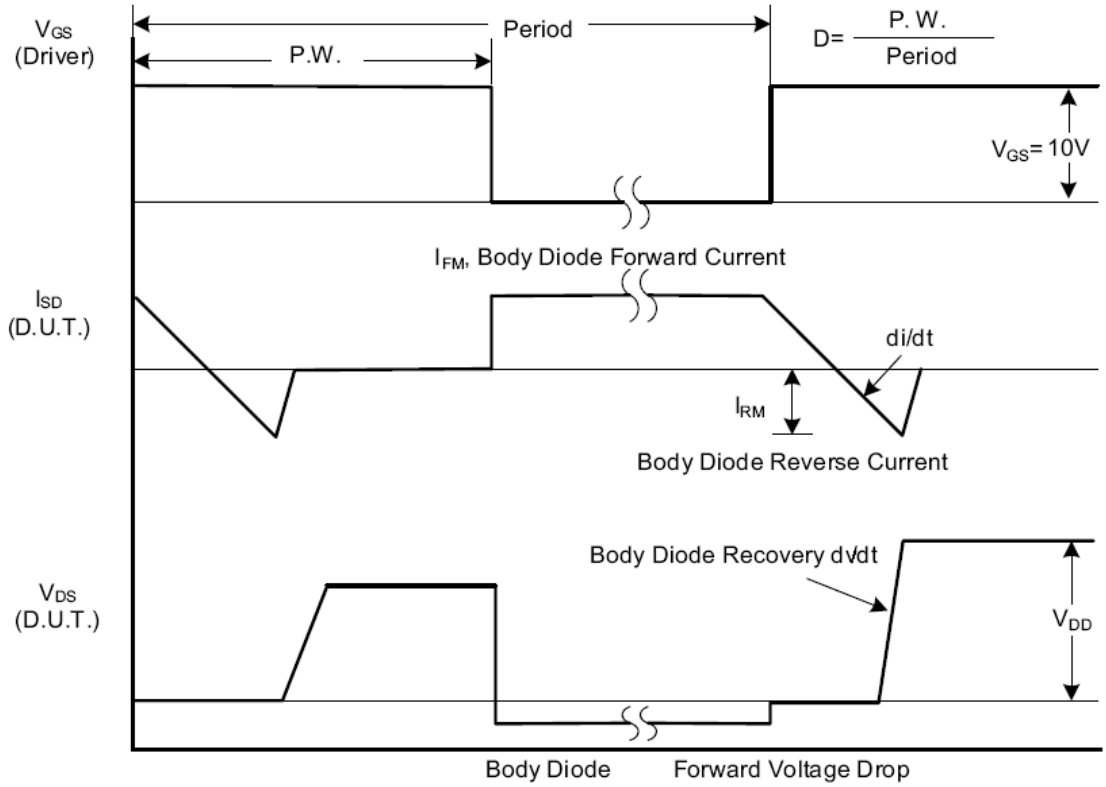


Fig. 1.2 Peak Diode Recovery dv/dt Waveforms

Test Circuits and Waveforms (Cont.)

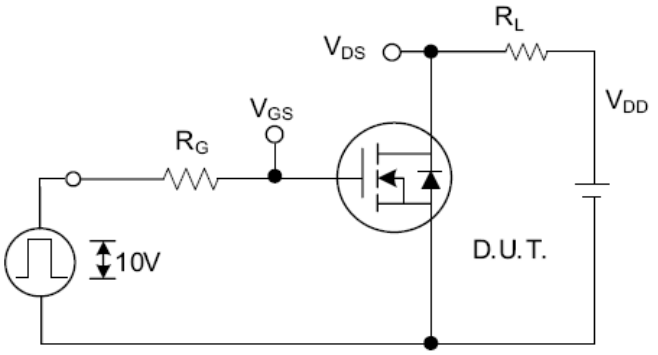


Fig. 2.1 Switching Test Circuit

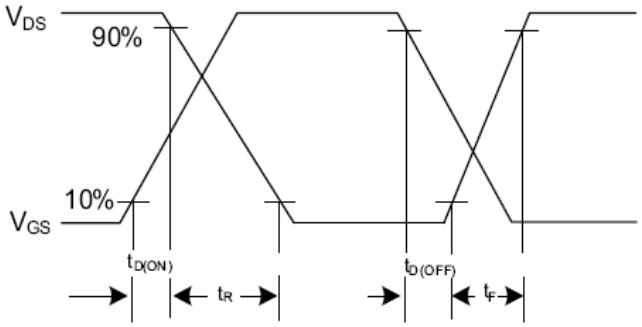


Fig. 2.2 Switching Waveforms

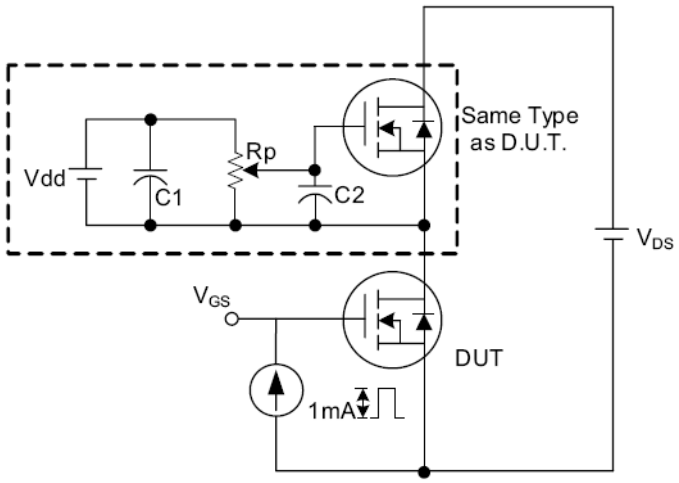


Fig. 3 . 1 Gate Charge Test Circuit

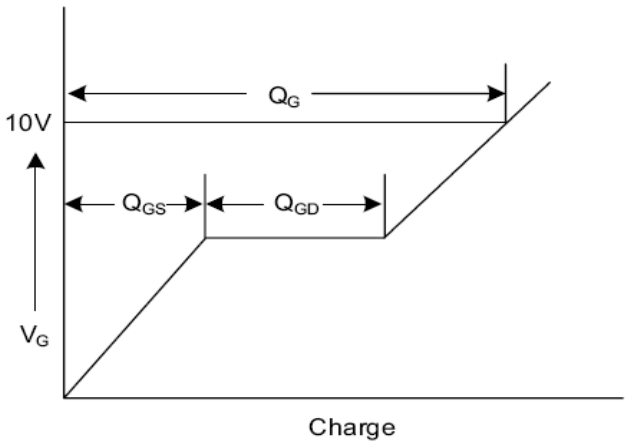


Fig. 3 . 2 Gate Charge Waveform

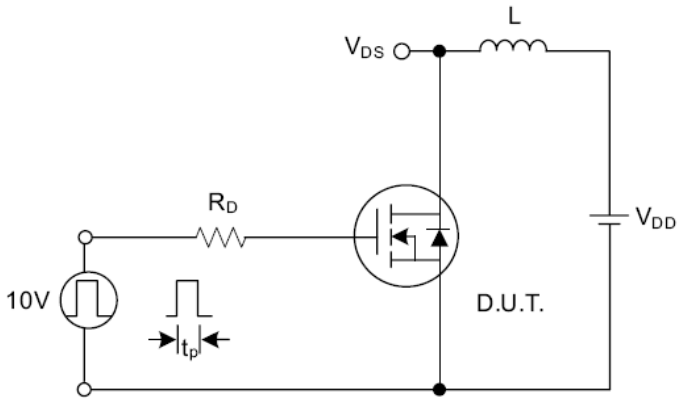


Fig. 4.1 Unclamped Inductive Switching Test Circuit

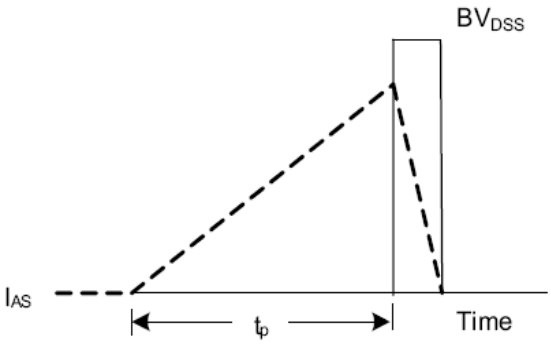


Fig. 4.2 Unclamped Inductive Switching Waveforms

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